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Applications of "[Embedded - Microcontrollers](#)"

Details

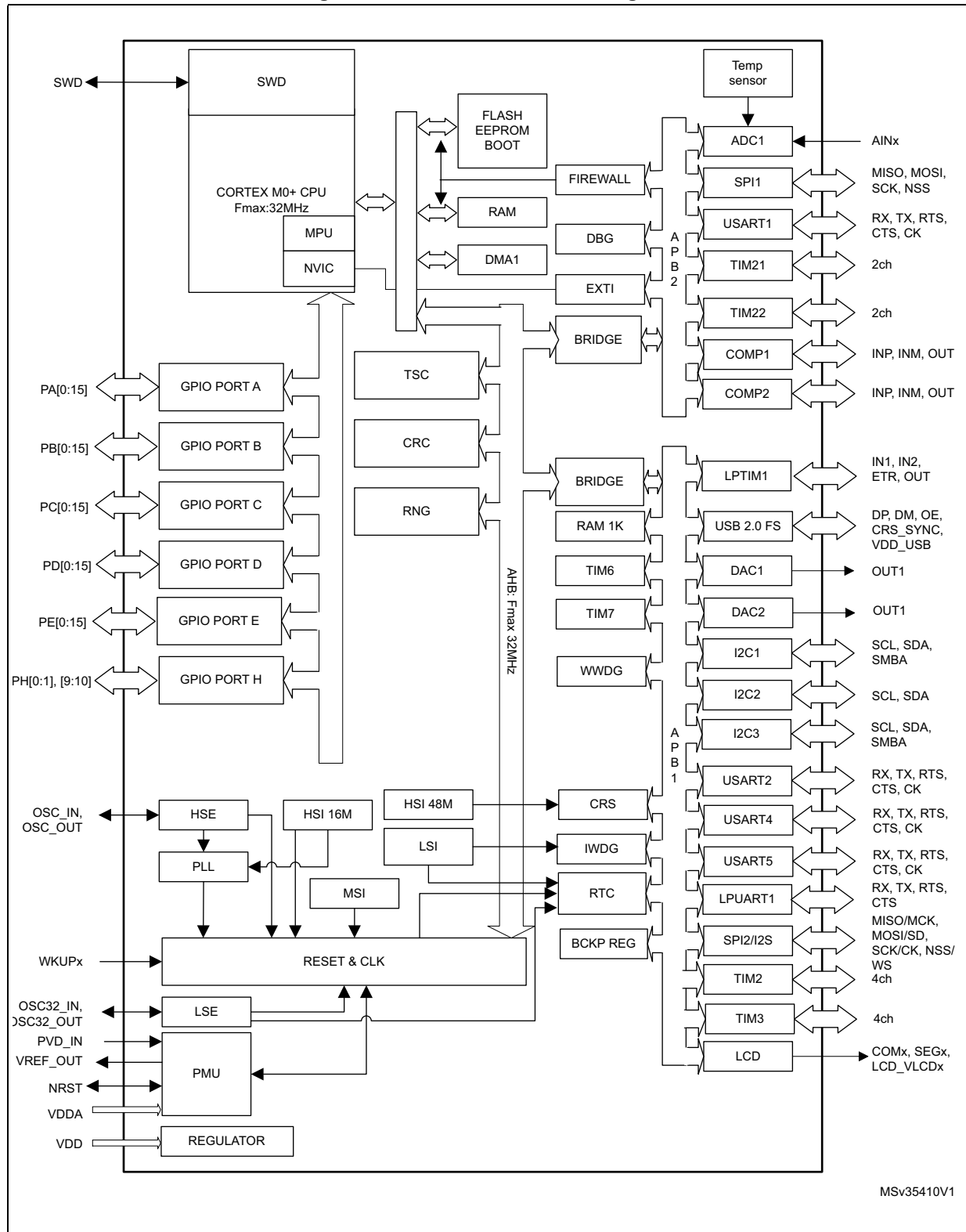
Product Status	Active
Core Processor	ARM® Cortex®-M0+
Core Size	32-Bit Single-Core
Speed	32MHz
Connectivity	I ² C, IrDA, LINbus, SPI, UART/USART, USB
Peripherals	Brown-out Detect/Reset, DMA, I ² S, LCD, POR, PWM, WDT
Number of I/O	50
Program Memory Size	128KB (128K x 8)
Program Memory Type	FLASH
EEPROM Size	6K x 8
RAM Size	20K x 8
Voltage - Supply (Vcc/Vdd)	1.8V ~ 3.6V
Data Converters	A/D 15x12b; D/A 2x12b
Oscillator Type	Internal
Operating Temperature	-40°C ~ 85°C (TA)
Mounting Type	Surface Mount
Package / Case	64-UFBGA
Supplier Device Package	64-UFBGA (5x5)
Purchase URL	https://www.e-xfl.com/product-detail/stmicroelectronics/stm32l073rbh6

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Figure 1. STM32L073xx block diagram



3 Functional overview

3.1 Low-power modes

The ultra-low-power STM32L073xx support dynamic voltage scaling to optimize its power consumption in Run mode. The voltage from the internal low-drop regulator that supplies the logic can be adjusted according to the system's maximum operating frequency and the external voltage supply.

There are three power consumption ranges:

- Range 1 (V_{DD} range limited to 1.71-3.6 V), with the CPU running at up to 32 MHz
- Range 2 (full V_{DD} range), with a maximum CPU frequency of 16 MHz
- Range 3 (full V_{DD} range), with a maximum CPU frequency limited to 4.2 MHz

Seven low-power modes are provided to achieve the best compromise between low-power consumption, short startup time and available wakeup sources:

- **Sleep mode**

In Sleep mode, only the CPU is stopped. All peripherals continue to operate and can wake up the CPU when an interrupt/event occurs. Sleep mode power consumption at 16 MHz is about 1 mA with all peripherals off.

- **Low-power run mode**

This mode is achieved with the multispeed internal (MSI) RC oscillator set to the low-speed clock (max 131 kHz), execution from SRAM or Flash memory, and internal regulator in low-power mode to minimize the regulator's operating current. In Low-power run mode, the clock frequency and the number of enabled peripherals are both limited.

- **Low-power sleep mode**

This mode is achieved by entering Sleep mode with the internal voltage regulator in low-power mode to minimize the regulator's operating current. In Low-power sleep mode, both the clock frequency and the number of enabled peripherals are limited; a typical example would be to have a timer running at 32 kHz.

When wakeup is triggered by an event or an interrupt, the system reverts to the Run mode with the regulator on.

Stop mode with RTC

The Stop mode achieves the lowest power consumption while retaining the RAM and register contents and real time clock. All clocks in the V_{CORE} domain are stopped, the PLL, MSI RC, HSE crystal and HSI RC oscillators are disabled. The LSE or LSI is still running. The voltage regulator is in the low-power mode.

Some peripherals featuring wakeup capability can enable the HSI RC during Stop mode to detect their wakeup condition.

The device can be woken up from Stop mode by any of the EXTI line, in 3.5 μ s, the processor can serve the interrupt or resume the code. The EXTI line source can be any GPIO. It can be the PVD output, the comparator 1 event or comparator 2 event (if internal reference voltage is on), it can be the RTC alarm/tamper/timestamp/wakeup events, the USB/USART/I2C/LPUART/LPTIMER wakeup events.

Table 3. Functionalities depending on the operating power supply range

Operating power supply range	Functionalities depending on the operating power supply range			
	DAC and ADC operation	Dynamic voltage scaling range	I/O operation	USB
$V_{DD} = 1.65$ to 1.71 V	ADC only, conversion time up to 570 ksp/s	Range 2 or range 3	Degraded speed performance	Not functional
$V_{DD} = 1.71$ to 1.8 V ⁽¹⁾	ADC only, conversion time up to 1.14 Msp/s	Range 1, range 2 or range 3	Degraded speed performance	Functional ⁽²⁾
$V_{DD} = 1.8$ to 2.0 V ⁽¹⁾	Conversion time up to 1.14 Msp/s	Range 1, range 2 or range 3	Degraded speed performance	Functional ⁽²⁾
$V_{DD} = 2.0$ to 2.4 V	Conversion time up to 1.14 Msp/s	Range 1, range 2 or range 3	Full speed operation	Functional ⁽²⁾
$V_{DD} = 2.4$ to 3.6 V	Conversion time up to 1.14 Msp/s	Range 1, range 2 or range 3	Full speed operation	Functional ⁽²⁾

1. CPU frequency changes from initial to final must respect "fcpu initial < 4*fcpu final". It must also respect 5 μ s delay between two changes. For example to switch from 4.2 MHz to 32 MHz, you can switch from 4.2 MHz to 16 MHz, wait 5 μ s, then switch from 16 MHz to 32 MHz.
2. To be USB compliant from the I/O voltage standpoint, the minimum V_{DD_USB} is 3.0 V.

Table 4. CPU frequency range depending on dynamic voltage scaling

CPU frequency range	Dynamic voltage scaling range
16 MHz to 32 MHz (1ws) 32 kHz to 16 MHz (0ws)	Range 1
8 MHz to 16 MHz (1ws) 32 kHz to 8 MHz (0ws)	Range 2
32 kHz to 4.2 MHz (0ws)	Range 3

3.4 Reset and supply management

3.4.1 Power supply schemes

- $V_{DD} = 1.65$ to 3.6 V: external power supply for I/Os and the internal regulator. Provided externally through V_{DD} pins.
- V_{SSA} , $V_{DDA} = 1.65$ to 3.6 V: external analog power supplies for ADC reset blocks, RCs and PLL. V_{DDA} and V_{SSA} must be connected to V_{DD} and V_{SS} , respectively.
- $V_{DD_USB} = 1.65$ to 3.6 V: external power supply for USB transceiver, USB_DM (PA11) and USB_DP (PA12). To guarantee a correct voltage level for USB communication V_{DD_USB} must be above 3.0 V. If USB is not used this pin must be tied to V_{DD} .

3.4.2 Power supply supervisor

The devices have an integrated ZEROPOWER power-on reset (POR)/power-down reset (PDR) that can be coupled with a brownout reset (BOR) circuitry.

Two versions are available:

- The version with BOR activated at power-on operates between 1.8 V and 3.6 V.
- The other version without BOR operates between 1.65 V and 3.6 V.

After the V_{DD} threshold is reached (1.65 V or 1.8 V depending on the BOR which is active or not at power-on), the option byte loading process starts, either to confirm or modify default thresholds, or to disable the BOR permanently: in this case, the V_{DD} min value becomes 1.65 V (whatever the version, BOR active or not, at power-on).

When BOR is active at power-on, it ensures proper operation starting from 1.8 V whatever the power ramp-up phase before it reaches 1.8 V. When BOR is not active at power-up, the power ramp-up should guarantee that 1.65 V is reached on V_{DD} at least 1 ms after it exits the POR area.

Five BOR thresholds are available through option bytes, starting from 1.8 V to 3 V. To reduce the power consumption in Stop mode, it is possible to automatically switch off the internal reference voltage (V_{REFINT}) in Stop mode. The device remains in reset mode when V_{DD} is below a specified threshold, $V_{POR/PDR}$ or V_{BOR} , without the need for any external reset circuit.

Note: *The start-up time at power-on is typically 3.3 ms when BOR is active at power-up, the start-up time at power-on can be decreased down to 1 ms typically for devices with BOR inactive at power-up.*

The devices feature an embedded programmable voltage detector (PVD) that monitors the $V_{DD/VDDA}$ power supply and compares it to the V_{PVD} threshold. This PVD offers 7 different levels between 1.85 V and 3.05 V, chosen by software, with a step around 200 mV. An interrupt can be generated when $V_{DD/VDDA}$ drops below the V_{PVD} threshold and/or when $V_{DD/VDDA}$ is higher than the V_{PVD} threshold. The interrupt service routine can then generate a warning message and/or put the MCU into a safe state. The PVD is enabled by software.

- **Startup clock**

After reset, the microcontroller restarts by default with an internal 2.1 MHz clock (MSI). The prescaler ratio and clock source can be changed by the application program as soon as the code execution starts.

- **Clock security system (CSS)**

This feature can be enabled by software. If an HSE clock failure occurs, the master clock is automatically switched to HSI and a software interrupt is generated if enabled.

Another clock security system can be enabled, in case of failure of the LSE it provides an interrupt or wakeup event which is generated if enabled.

- **Clock-out capability (MCO: microcontroller clock output)**

It outputs one of the internal clocks for external use by the application.

Several prescalers allow the configuration of the AHB frequency, each APB (APB1 and APB2) domains. The maximum frequency of the AHB and the APB domains is 32 MHz. See [Figure 2](#) for details on the clock tree.

3.17 Timers and watchdogs

The ultra-low-power STM32L073xx devices include three general-purpose timers, one low-power timer (LPTIM), one basic timer, two watchdog timers and the SysTick timer.

[Table 10](#) compares the features of the general-purpose and basic timers.

Table 10. Timer feature comparison

Timer	Counter resolution	Counter type	Prescaler factor	DMA request generation	Capture/compare channels	Complementary outputs
TIM2, TIM3	16-bit	Up, down, up/down	Any integer between 1 and 65536	Yes	4	No
TIM21, TIM22	16-bit	Up, down, up/down	Any integer between 1 and 65536	No	2	No
TIM6, TIM7	16-bit	Up	Any integer between 1 and 65536	Yes	0	No

3.17.1 General-purpose timers (TIM2, TIM3, TIM21 and TIM22)

There are four synchronizable general-purpose timers embedded in the STM32L073xx device (see [Table 10](#) for differences).

TIM2, TIM3

TIM2 and TIM3 are based on 16-bit auto-reload up/down counter. It includes a 16-bit prescaler. It features four independent channels each for input capture/output compare, PWM or one-pulse mode output.

The TIM2/TIM3 general-purpose timers can work together or with the TIM21 and TIM22 general-purpose timers via the Timer Link feature for synchronization or event chaining. Their counter can be frozen in debug mode. Any of the general-purpose timers can be used to generate PWM outputs.

TIM2/TIM3 have independent DMA request generation.

These timers are capable of handling quadrature (incremental) encoder signals and the digital outputs from 1 to 3 hall-effect sensors.

TIM21 and TIM22

TIM21 and TIM22 are based on a 16-bit auto-reload up/down counter. They include a 16-bit prescaler. They have two independent channels for input capture/output compare, PWM or one-pulse mode output. They can work together and be synchronized with the TIM2/TIM3, full-featured general-purpose timers.

They can also be used as simple time bases and be clocked by the LSE clock source (32.768 kHz) to provide time bases independent from the main CPU clock.

Only a 32.768 kHz clock (LSE) is needed to allow LPUART communication up to 9600 baud. Therefore, even in Stop mode, the LPUART can wait for an incoming frame while having an extremely low energy consumption. Higher speed clock can be used to reach higher baudrates.

LPUART interface can be served by the DMA controller.

3.18.4 Serial peripheral interface (SPI)/Inter-integrated sound (I2S)

Up to two SPIs are able to communicate at up to 16 Mbits/s in slave and master modes in full-duplex and half-duplex communication modes. The 3-bit prescaler gives 8 master mode frequencies and the frame is configurable to 8 bits or 16 bits. The hardware CRC generation/verification supports basic SD Card/MMC modes.

The USARTs with synchronous capability can also be used as SPI master.

One standard I2S interfaces (multiplexed with SPI2) is available. It can operate in master or slave mode, and can be configured to operate with a 16-/32-bit resolution as input or output channels. Audio sampling frequencies from 8 kHz up to 192 kHz are supported. When the I2S interfaces is configured in master mode, the master clock can be output to the external DAC/CODEC at 256 times the sampling frequency.

The SPIs can be served by the DMA controller.

Refer to [Table 14](#) for the differences between SPI1 and SPI2.

Table 14. SPI/I2S implementation

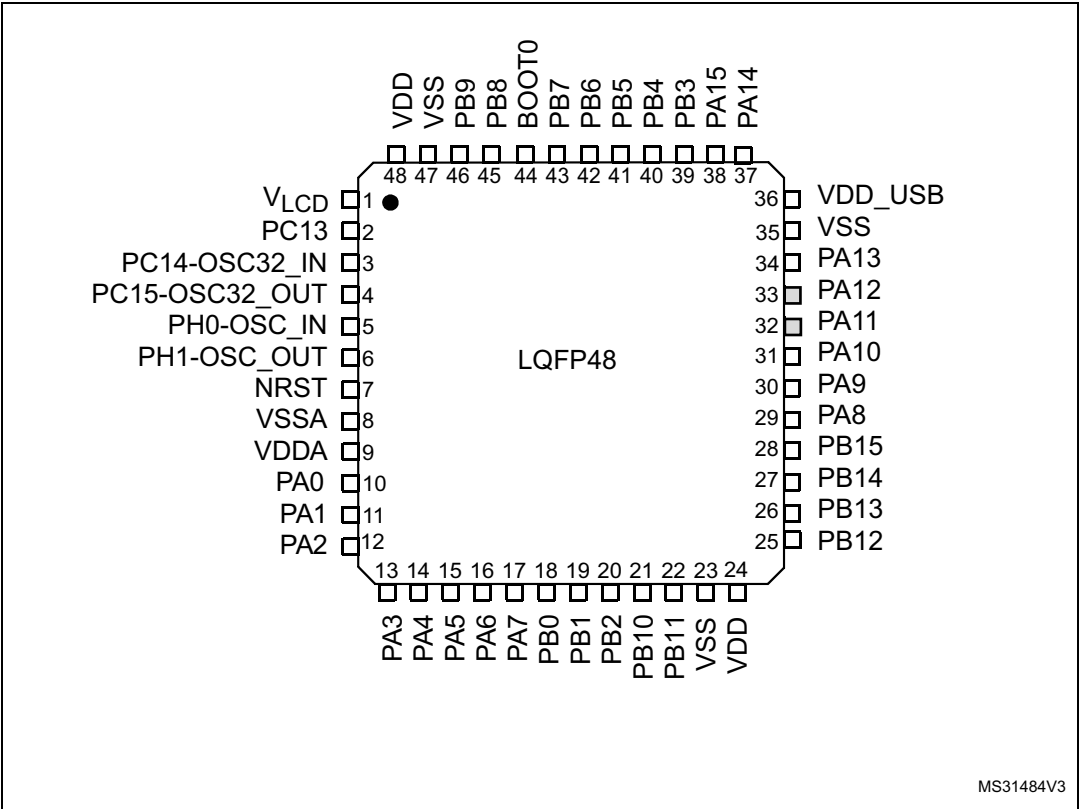
SPI features ⁽¹⁾	SPI1	SPI2
Hardware CRC calculation	X	X
I2S mode	-	X
TI mode	X	X

1. X = supported.

3.18.5 Universal serial bus (USB)

The STM32L073xx embeds a full-speed USB device peripheral compliant with the USB specification version 2.0. The internal USB PHY supports USB FS signaling, embedded DP pull-up and also battery charging detection according to Battery Charging Specification Revision 1.2. The USB interface implements a full-speed (12 Mbit/s) function interface with added support for USB 2.0 Link Power Management. It has software-configurable endpoint setting with packet memory up to 1 KB and suspend/resume support. It requires a precise 48 MHz clock which can be generated from the internal main PLL (the clock source must use a HSE crystal oscillator) or by the internal 48 MHz oscillator in automatic trimming mode. The synchronization for this oscillator can be taken from the USB data stream itself (SOF signalization) which allows crystal-less operation.

Figure 7. STM32L073xx LQFP48 pinout - 7 x 7 mm



1. The above figure shows the package top view.
2. I/O pin supplied by VDD_USB.

Table 15. Legend/abbreviations used in the pinout table

Name	Abbreviation	Definition
Pin name	Unless otherwise specified in brackets below the pin name, the pin function during and after reset is the same as the actual pin name	
Pin type	S	Supply pin
	I	Input only pin
	I/O	Input / output pin
I/O structure	FT	5 V tolerant I/O
	FTf	5 V tolerant I/O, FM+ capable
	TC	Standard 3.3V I/O
	B	Dedicated BOOT0 pin
	RST	Bidirectional reset pin with embedded weak pull-up resistor
Notes	Unless otherwise specified by a note, all I/Os are set as floating inputs during and after reset.	

6.1.6 Power supply scheme

Figure 11. Power supply scheme

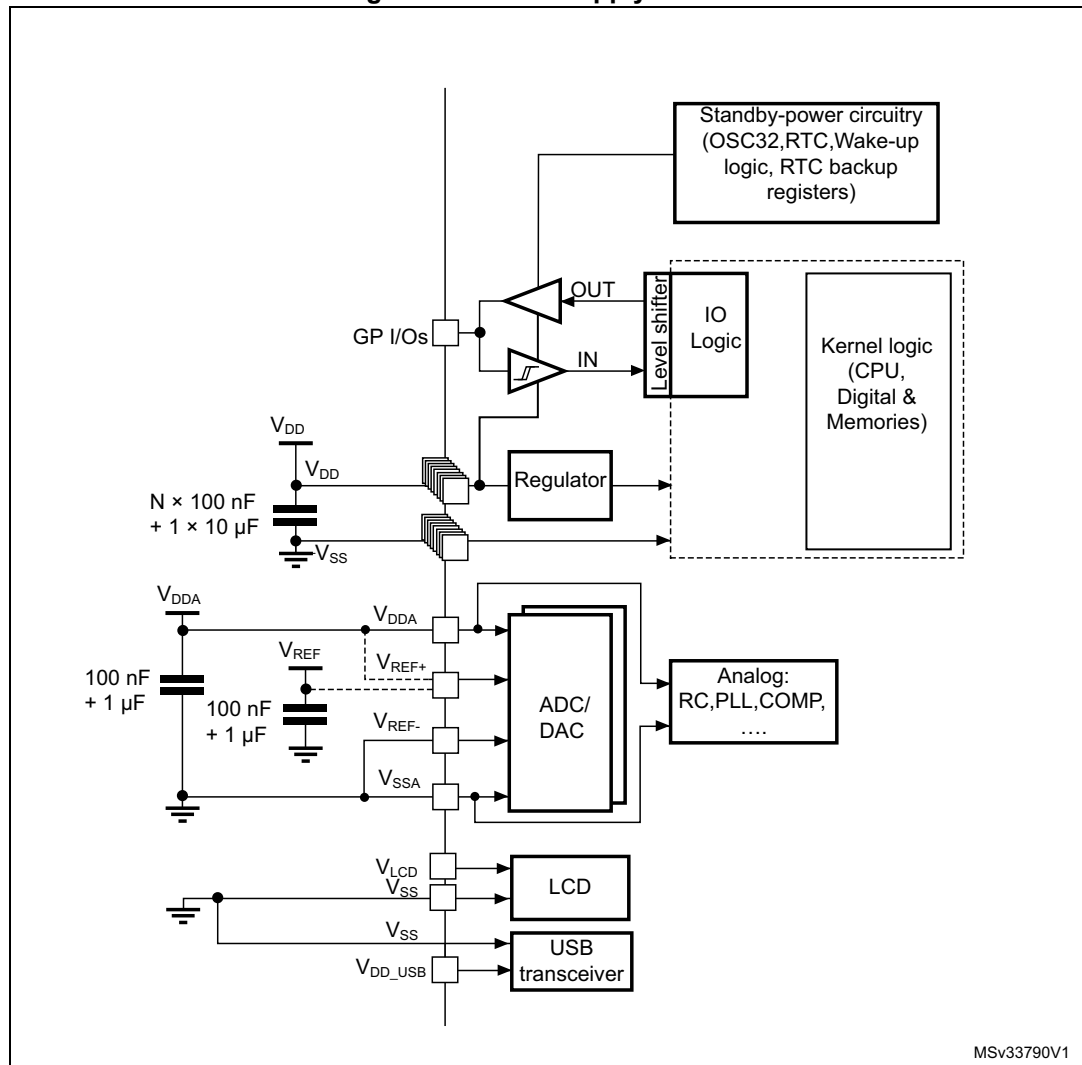


Table 26. General operating conditions (continued)

Symbol	Parameter	Conditions	Min	Max	Unit
T _A	Temperature range	Maximum power dissipation (range 6)	−40	85	°C
		Maximum power dissipation (range 7)	−40	105	
		Maximum power dissipation (range 3)	−40	125	
T _J	Junction temperature range (range 6)	−40 °C ≤ T _A ≤ 85 °	−40	105	
	Junction temperature range (range 7)	−40 °C ≤ T _A ≤ 105 °C	−40	125	
	Junction temperature range (range 3)	−40 °C ≤ T _A ≤ 125 °C	−40	130	

1. It is recommended to power V_{DD} and V_{DDA} from the same source. A maximum difference of 300 mV between V_{DD} and V_{DDA} can be tolerated during power-up and normal operation.
2. V_{DD_USB} must respect the following conditions:
 - When V_{DD} is powered on (V_{DD} < V_{DD_min}), V_{DD_USB} should be always lower than V_{DD}.
 - When V_{DD} is powered down (V_{DD} < V_{DD_min}), V_{DD_USB} should be always lower than V_{DD}.
 - In operating mode, V_{DD_USB} could be lower or higher V_{DD}.
 - If the USB is not used, V_{DD_USB} must range from V_{DD_min} to V_{DD_max} to be able to use PA11 and PA12 as standard I/Os.
3. To sustain a voltage higher than V_{DD}+0.3V, the internal pull-up/pull-down resistors must be disabled.
4. If T_A is lower, higher P_D values are allowed as long as T_J does not exceed T_J max (see [Table 90: Thermal characteristics on page 134](#)).

Table 27. Embedded reset and power control block characteristics (continued)

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
V_{PVD6}	PVD threshold 6	Falling edge	2.97	3.05	3.09	V
		Rising edge	3.08	3.15	3.20	
V_{hyst}	Hysteresis voltage	BOR0 threshold	-	40	-	mV
		All BOR and PVD thresholds excepting BOR0	-	100	-	

1. Guaranteed by characterization results.

2. Valid for device version without BOR at power up. Please see option "D" in Ordering information scheme for more details.

6.3.3 Embedded internal reference voltage

The parameters given in [Table 29](#) are based on characterization results, unless otherwise specified.

Table 28. Embedded internal reference voltage calibration values

Calibration value name	Description	Memory address
VREFINT_CAL	Raw data acquired at temperature of 25 °C $V_{DDA} = 3\text{ V}$	0x1FF8 0078 - 0x1FF8 0079

Table 29. Embedded internal reference voltage⁽¹⁾

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
$V_{REFINT\ out}^{(2)}$	Internal reference voltage	$-40\text{ °C} < T_J < +125\text{ °C}$	1.202	1.224	1.242	V
$T_{VREFINT}$	Internal reference startup time	-	-	2	3	ms
V_{VREF_MEAS}	V_{DDA} and V_{REF+} voltage during V_{REFINT} factory measure	-	2.99	3	3.01	V
A_{VREF_MEAS}	Accuracy of factory-measured V_{REFINT} value ⁽³⁾	Including uncertainties due to ADC and V_{DDA}/V_{REF+} values	-	-	±5	mV
$T_{Coeff}^{(4)}$	Temperature coefficient	$-40\text{ °C} < T_J < +125\text{ °C}$	-	25	100	ppm/°C
$A_{Coeff}^{(4)}$	Long-term stability	1000 hours, $T = 25\text{ °C}$	-	-	1000	ppm
$V_{DDCoeff}^{(4)}$	Voltage coefficient	$3.0\text{ V} < V_{DDA} < 3.6\text{ V}$	-	-	2000	ppm/V
$T_{S_vrefint}^{(4)(5)}$	ADC sampling time when reading the internal reference voltage	-	5	10	-	µs
$T_{ADC_BUF}^{(4)}$	Startup time of reference voltage buffer for ADC	-	-	-	10	µs
$I_{BUF_ADC}^{(4)}$	Consumption of reference voltage buffer for ADC	-	-	13.5	25	µA
$I_{VREF_OUT}^{(4)}$	VREF_OUT output current ⁽⁶⁾	-	-	-	1	µA
$C_{VREF_OUT}^{(4)}$	VREF_OUT output load	-	-	-	50	pF

Figure 14. I_{DD} vs V_{DD} , at $T_A = 25/55/85/105\text{ }^{\circ}\text{C}$, Run mode, code running from Flash memory, Range 2, HSE, 1WS

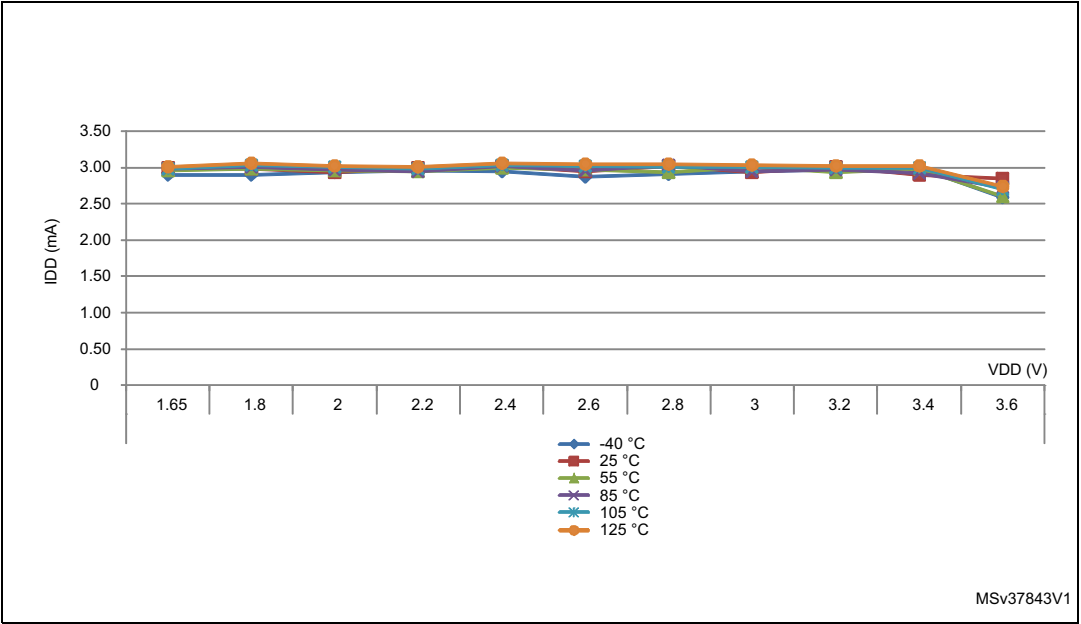


Figure 15. I_{DD} vs V_{DD} , at $T_A = 25/55/85/105\text{ }^{\circ}\text{C}$, Run mode, code running from Flash memory, Range 2, HSI16, 1WS

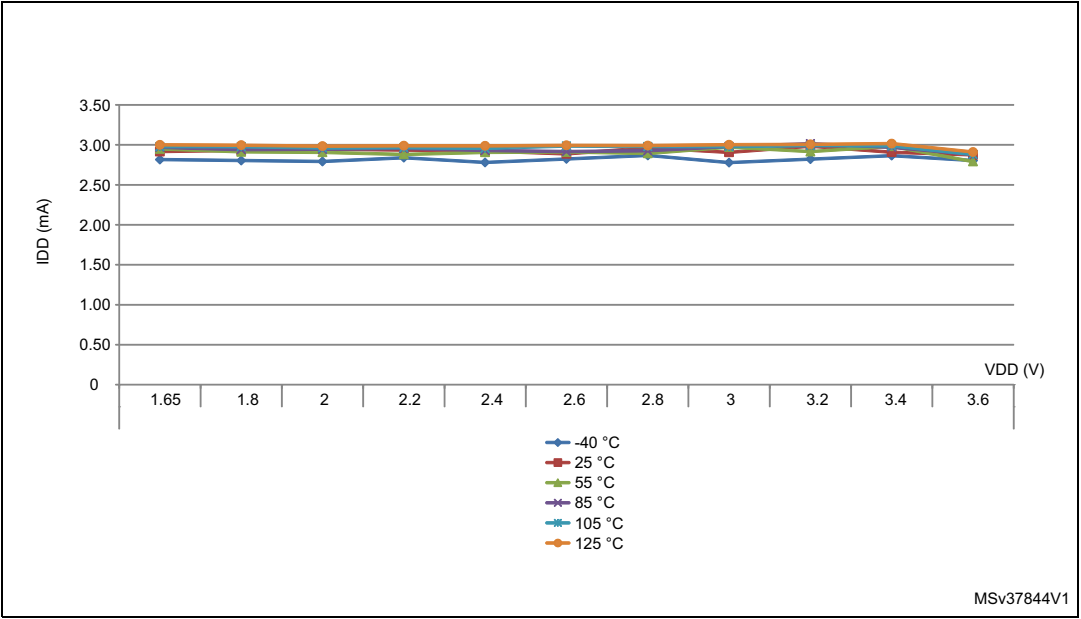
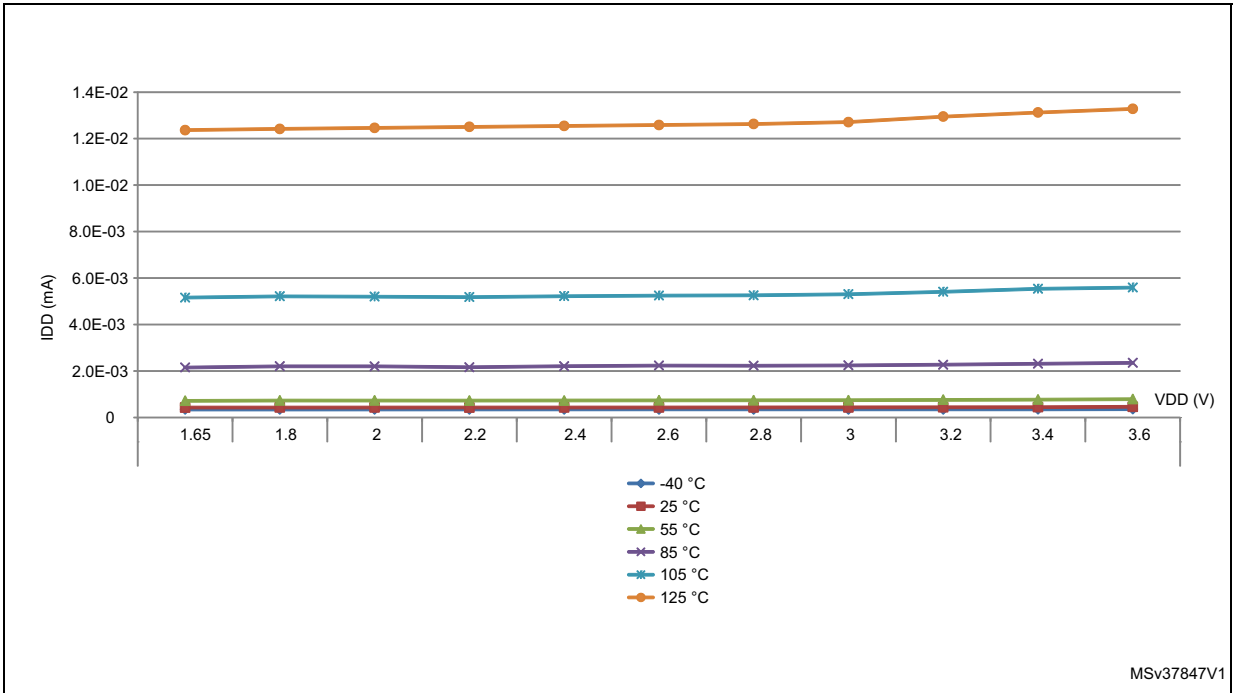


Figure 18. I_{DD} vs V_{DD} , at $T_A = 25/55/85/105/125\text{ }^{\circ}\text{C}$, Stop mode with RTC disabled, all clocks off



MSv37847V1

Table 38. Typical and maximum current consumptions in Standby mode

Symbol	Parameter	Conditions		Typ	Max ⁽¹⁾	Unit
I_{DD} (Standby)	Supply current in Standby mode	Independent watchdog and LSI enabled	$T_A = -40\text{ to }25\text{ }^{\circ}\text{C}$	0,855	1,70	μA
			$T_A = 55\text{ }^{\circ}\text{C}$	-	2,90	
			$T_A = 85\text{ }^{\circ}\text{C}$	-	3,30	
			$T_A = 105\text{ }^{\circ}\text{C}$	-	4,10	
			$T_A = 125\text{ }^{\circ}\text{C}$	-	8,50	
		Independent watchdog and LSI off	$T_A = -40\text{ to }25\text{ }^{\circ}\text{C}$	0,29	0,60	
			$T_A = 55\text{ }^{\circ}\text{C}$	0,32	1,20	
			$T_A = 85\text{ }^{\circ}\text{C}$	0,5	2,30	
			$T_A = 105\text{ }^{\circ}\text{C}$	0,94	3,00	
			$T_A = 125\text{ }^{\circ}\text{C}$	2,6	7,00	

1. Guaranteed by characterization results at 125 °C, unless otherwise specified

Output voltage levels

Unless otherwise specified, the parameters given in [Table 61](#) are derived from tests performed under ambient temperature and V_{DD} supply voltage conditions summarized in [Table 26](#). All I/Os are CMOS and TTL compliant.

Table 61. Output voltage characteristics

Symbol	Parameter	Conditions	Min	Max	Unit
$V_{OL}^{(1)}$	Output low level voltage for an I/O pin	CMOS port ⁽²⁾ , $I_{IO} = +8 \text{ mA}$ $2.7 \text{ V} \leq V_{DD} \leq 3.6 \text{ V}$	-	0.4	V
$V_{OH}^{(3)}$	Output high level voltage for an I/O pin		$V_{DD}-0.4$	-	
$V_{OL}^{(1)}$	Output low level voltage for an I/O pin	TTL port ⁽²⁾ , $I_{IO} = +8 \text{ mA}$ $2.7 \text{ V} \leq V_{DD} \leq 3.6 \text{ V}$	-	0.4	
$V_{OH}^{(3)(4)}$	Output high level voltage for an I/O pin	TTL port ⁽²⁾ , $I_{IO} = -6 \text{ mA}$ $2.7 \text{ V} \leq V_{DD} \leq 3.6 \text{ V}$	2.4	-	
$V_{OL}^{(1)(4)}$	Output low level voltage for an I/O pin	$I_{IO} = +15 \text{ mA}$ $2.7 \text{ V} \leq V_{DD} \leq 3.6 \text{ V}$	-	1.3	
$V_{OH}^{(3)(4)}$	Output high level voltage for an I/O pin	$I_{IO} = -15 \text{ mA}$ $2.7 \text{ V} \leq V_{DD} \leq 3.6 \text{ V}$	$V_{DD}-1.3$	-	
$V_{OL}^{(1)(4)}$	Output low level voltage for an I/O pin	$I_{IO} = +4 \text{ mA}$ $1.65 \text{ V} \leq V_{DD} < 3.6 \text{ V}$	-	0.45	
$V_{OH}^{(3)(4)}$	Output high level voltage for an I/O pin	$I_{IO} = -4 \text{ mA}$ $1.65 \text{ V} \leq V_{DD} \leq 3.6 \text{ V}$	$V_{DD}-0.45$	-	
$V_{OLFM+}^{(1)(4)}$	Output low level voltage for an FTf I/O pin in Fm+ mode	$I_{IO} = 20 \text{ mA}$ $2.7 \text{ V} \leq V_{DD} \leq 3.6 \text{ V}$	-	0.4	
		$I_{IO} = 10 \text{ mA}$ $1.65 \text{ V} \leq V_{DD} \leq 3.6 \text{ V}$	-	0.4	

1. The I_{IO} current sunk by the device must always respect the absolute maximum rating specified in [Table 24](#). The sum of the currents sunk by all the I/Os (I/O ports and control pins) must always be respected and must not exceed $\Sigma I_{IO(PIN)}$.
2. TTL and CMOS outputs are compatible with JEDEC standards JESD36 and JESD52.
3. The I_{IO} current sourced by the device must always respect the absolute maximum rating specified in [Table 24](#). The sum of the currents sourced by all the I/Os (I/O ports and control pins) must always be respected and must not exceed $\Sigma I_{IO(PIN)}$.
4. Guaranteed by characterization results.

Equation 1: R_{AIN} max formula

$$R_{AIN} < \frac{T_S}{f_{ADC} \times C_{ADC} \times \ln(2^{N+2})} - R_{ADC}$$

The simplified formula above ([Equation 1](#)) is used to determine the maximum external impedance allowed for an error below 1/4 of LSB. Here N = 12 (from 12-bit resolution).

Table 65. R_{AIN} max for $f_{ADC} = 16 \text{ MHz}^{(1)}$

T_S (cycles)	t_S (μs)	R_{AIN} max for fast channels ($k\Omega$)	R_{AIN} max for standard channels ($k\Omega$)						
			$V_{DD} > 2.7 \text{ V}$	$V_{DD} > 2.4 \text{ V}$	$V_{DD} > 2.0 \text{ V}$	$V_{DD} > 1.8 \text{ V}$	$V_{DD} > 1.75 \text{ V}$	$V_{DD} > 1.65 \text{ V}$ and $T_A > -10 \text{ }^\circ\text{C}$	$V_{DD} > 1.65 \text{ V}$ and $T_A > 25 \text{ }^\circ\text{C}$
1.5	0.09	0.5	< 0.1	NA	NA	NA	NA	NA	NA
3.5	0.22	1	0.2	< 0.1	NA	NA	NA	NA	NA
7.5	0.47	2.5	1.7	1.5	< 0.1	NA	NA	NA	NA
12.5	0.78	4	3.2	3	1	NA	NA	NA	NA
19.5	1.22	6.5	5.7	5.5	3.5	NA	NA	NA	< 0.1
39.5	2.47	13	12.2	12	10	NA	NA	NA	5
79.5	4.97	27	26.2	26	24	< 0.1	NA	NA	19
160.5	10.03	50	49.2	49	47	32	< 0.1	< 0.1	42

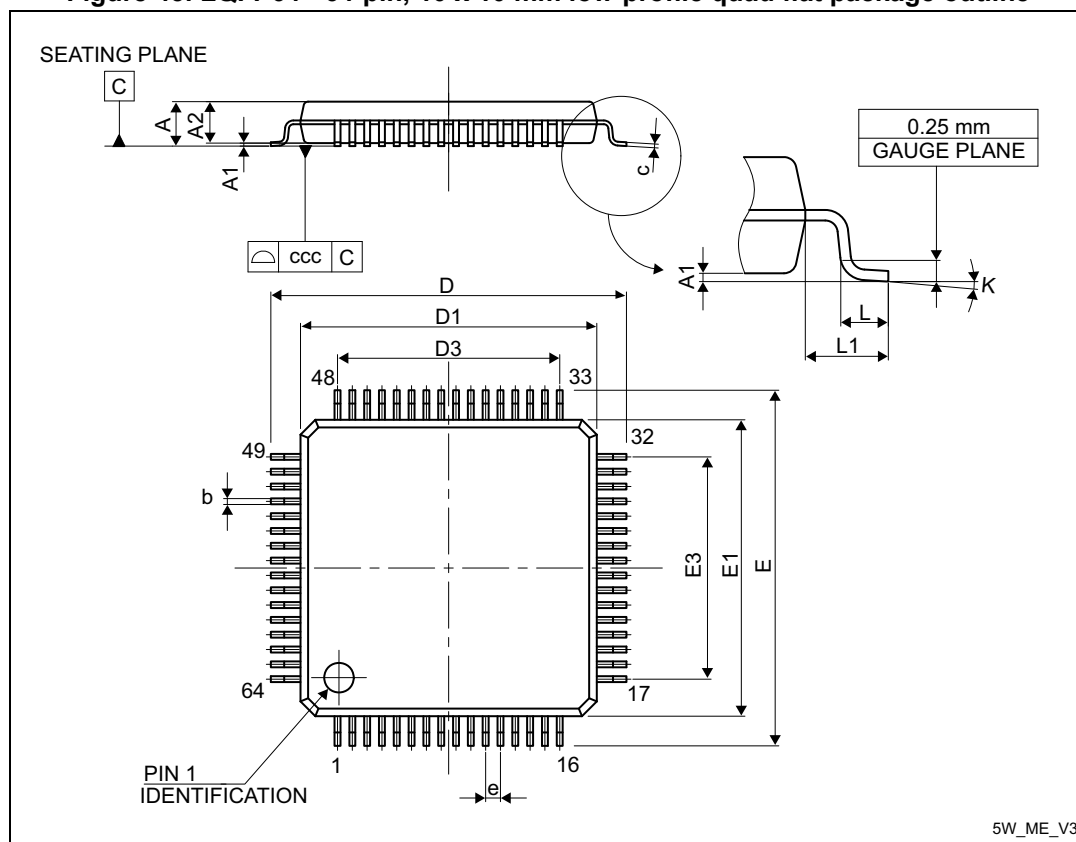
1. Guaranteed by design.

Table 66. ADC accuracy⁽¹⁾⁽²⁾⁽³⁾

Symbol	Parameter	Conditions	Min	Typ	Max	Unit
ET	Total unadjusted error	$1.65 \text{ V} < V_{DDA} = V_{REF+} < 3.6 \text{ V}$, range 1/2/3	-	2	4	LSB
EO	Offset error		-	1	2.5	
EG	Gain error		-	1	2	
EL	Integral linearity error		-	1.5	2.5	
ED	Differential linearity error		-	1	1.5	
ENOB	Effective number of bits		10.2	11	-	bits
	Effective number of bits (16-bit mode oversampling with ratio =256) ⁽⁴⁾		11.3	12.1	-	
SINAD	Signal-to-noise distortion		63	69	-	dB
SNR	Signal-to-noise ratio		63	69	-	
	Signal-to-noise ratio (16-bit mode oversampling with ratio =256) ⁽⁴⁾		70	76	-	
THD	Total harmonic distortion		-	-85	-73	

7.3 LQFP64 package information

Figure 45. LQFP64 - 64-pin, 10 x 10 mm low-profile quad flat package outline

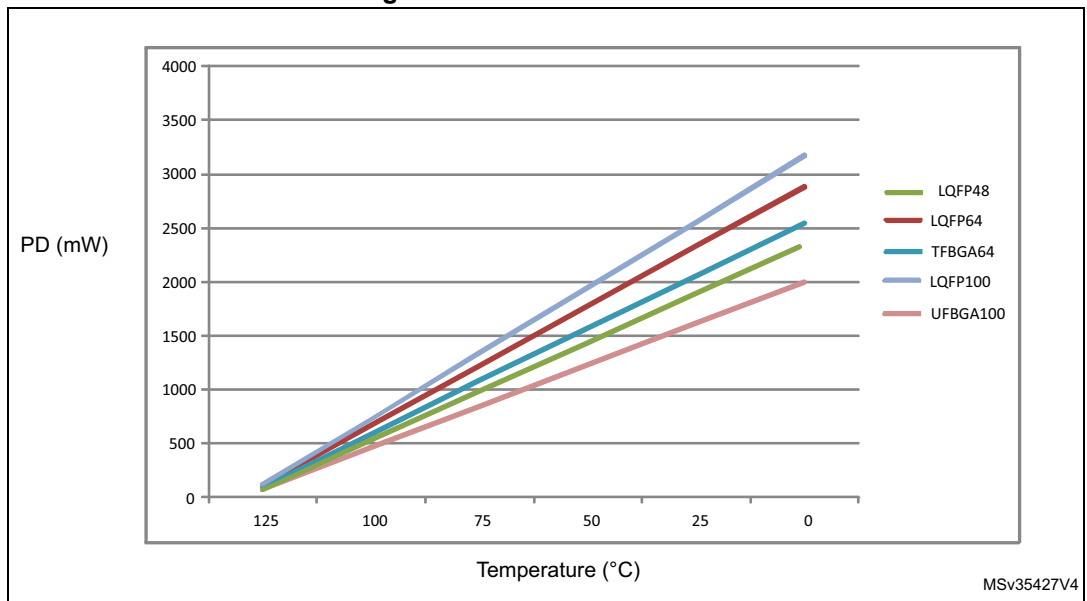


1. Drawing is not to scale.

Table 86. LQFP64 - 64-pin, 10 x 10 mm low-profile quad flat package mechanical data

Symbol	millimeters			inches ⁽¹⁾		
	Min	Typ	Max	Min	Typ	Max
A	-	-	1.600	-	-	0.0630
A1	0.050	-	0.150	0.0020	-	0.0059
A2	1.350	1.400	1.450	0.0531	0.0551	0.0571
b	0.170	0.220	0.270	0.0067	0.0087	0.0106
c	0.090	-	0.200	0.0035	-	0.0079
D	-	12.000	-	-	0.4724	-
D1	-	10.000	-	-	0.3937	-
D3	-	7.500	-	-	0.2953	-
E	-	12.000	-	-	0.4724	-
E1	-	10.000	-	-	0.3937	-

Figure 54. Thermal resistance



7.6.1 Reference document

JESD51-2 Integrated Circuits Thermal Test Method Environment Conditions - Natural Convection (Still Air). Available from www.jedec.org.

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